Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/789,503	LILLE, JEFFREY S.	LILLE, JEFFREY S.
Examiner	Art Unit	Art Unit
Paul D. Kim	3729	3729

	SEAR	CHED	
Class	Subclass	Date	Examiner
29	603.07 603.1 603.12 603.16 851	12/6/2005	PK
360	234.5		
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
Reviewed Parent Application 10/047,229 (US PAT. 6,725,526)	12/6/2005	РК
Text Search EAST/NPL (IEEE)	12/6/2005	PK
Updated Text Search EAST	10/17/2006	PK